

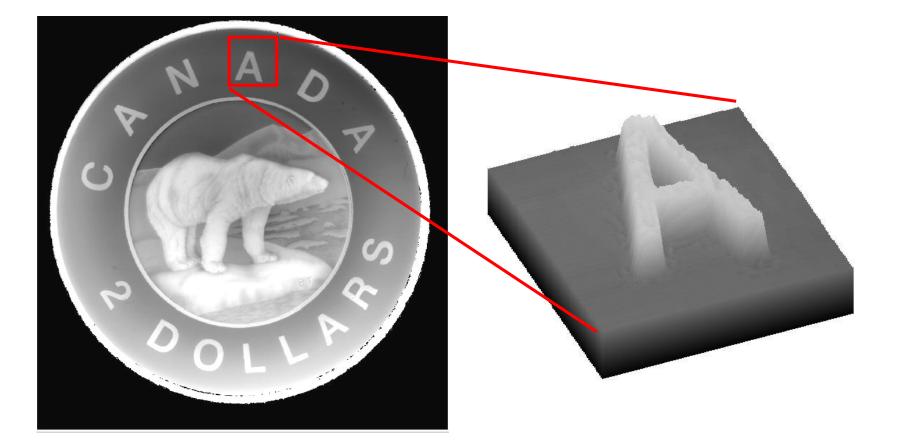
# Fiber-Based Profilometers and Their Applications

Novacam Technologies Inc.

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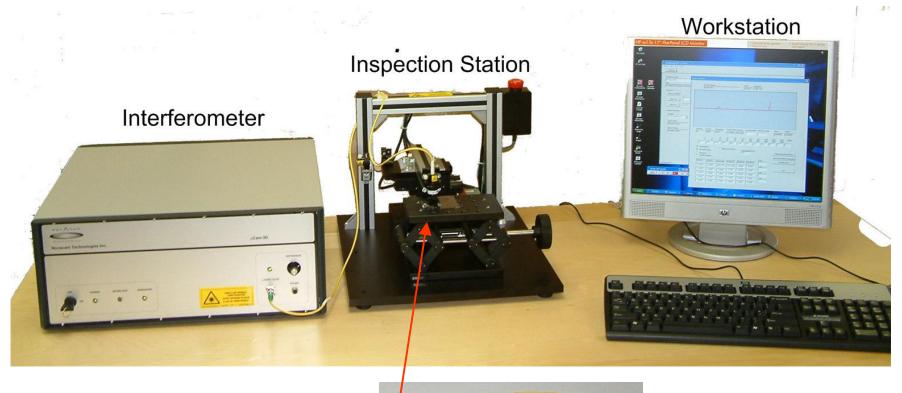
# 3D measurements with accuracy better then 1µm







### What Is Fiber-Based **Profilometry?**





Probe tip



# **Profilometry Applications**

#### 1) Profilometry

- Distance measurements => 3D surface map or profile
- Surface characterization roughness
- Hard to reach surfaces
- Hostile environments (cryogenic, high temp., radioactive)
- Volume loss
- High aspect ratio imaging
- 2) Thickness measurements of film or coating
  - Multi-layer film thickness measurements
  - Measurement of the refraction index
- 3) Cross section imaging
- 4) On-line industrial and lab applications



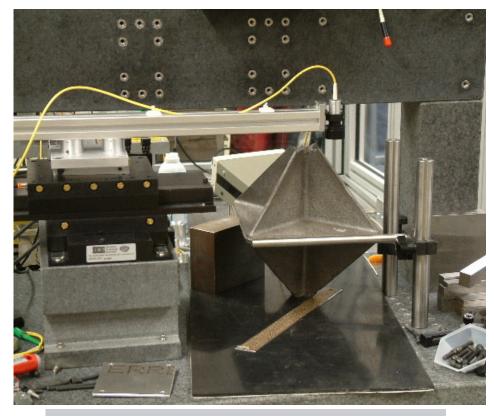
### Profilometry: Industrial Applications

- Semiconductor industry
- Aerospace industry
- Casting industry
- Optical industry
  - etching and deposition measurements for waveguides
  - inspection of optical components
- Forensic applications
  - bullet shape, cartridge, gun barrel inspection
- Fuel cell metrology
- **Glass industries:** thickness measurements
- **Plastic industry:** rheometric measurements

...and many other industries



### Typical Profilometry Setup With X-Y Slides

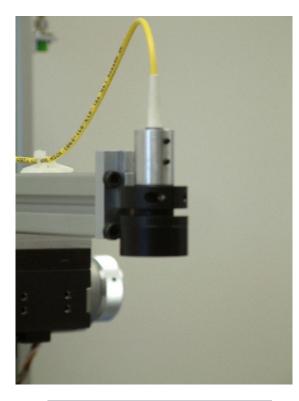


Standoff distance 150 mm or 6"

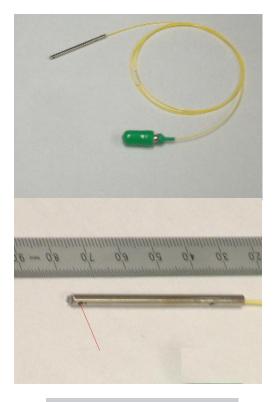
- Standoff distance, probe to object = few mm to 1m
- Accuracy of measurement still under 1µm
- Measuring one point at a time probe must be scanned to map whole surface
- Acquisition speed up to
  20,000 points per second



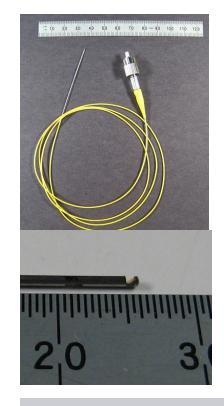
#### **Fiber Probes**



 $\Phi$  16mm probe (standard)



#### $\Phi$ 5mm probe



 $\Phi$  0.9mm probe

### **Small Diameter Fiber Probes**









# **Profilometry Applications**

#### 1) Profilometry

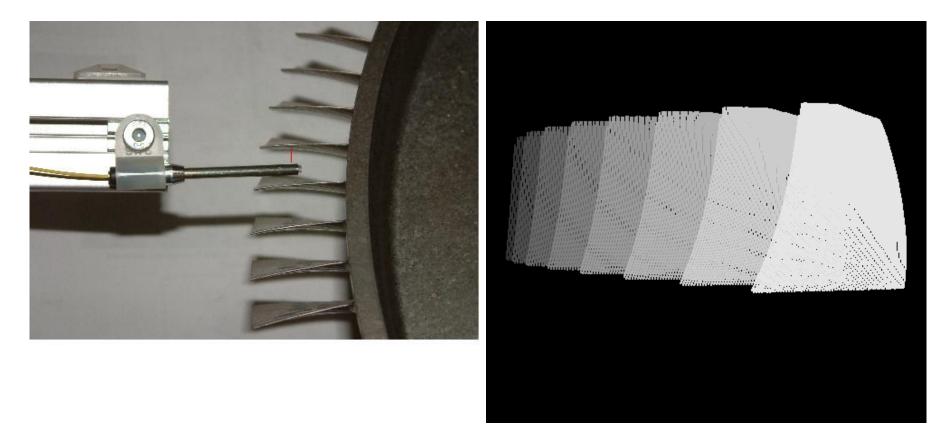
#### 2) Thickness measurements of film or coating

- 3) Cross section imaging
- 4) On-line industrial and lab applications



### Profilometry in Aerospace Industry

#### Profiling turbine blades in blisk assembly



Small fiber probe can image in between blisk blades

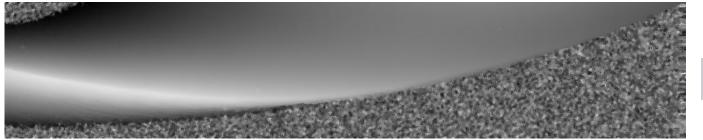


### **Blade Profiling of Tools**

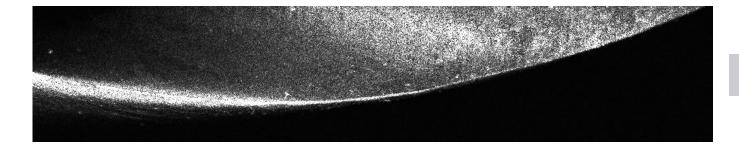
TECHNOLOGIES INC

#### Drill bit – high-aspect ration imaging





#### Height image

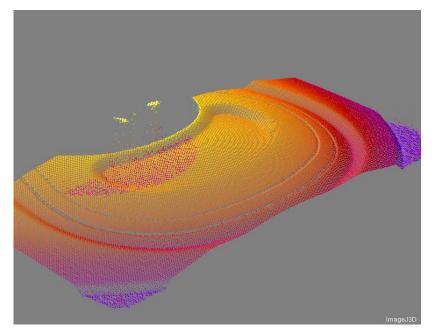


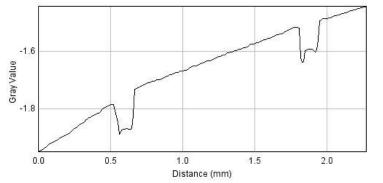
#### Intensity image

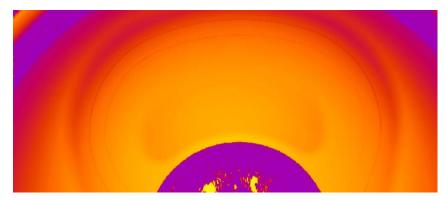


### Profilometry of High Aspect Ratio Imaging Features

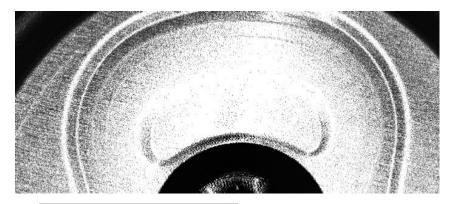
#### Profiling groove depth on cola can lid







Height image

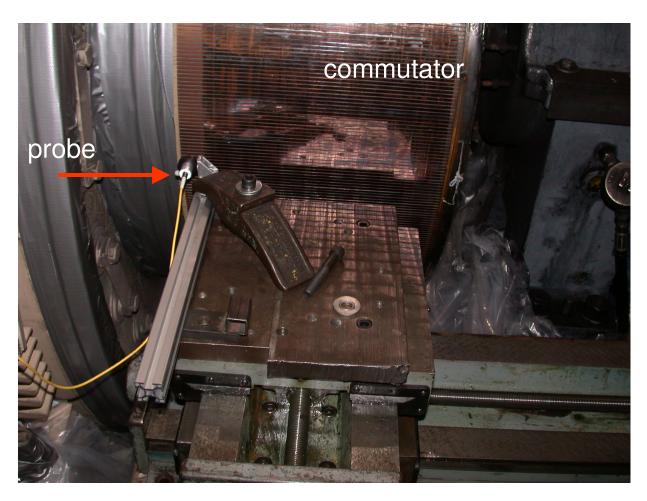


Intensity image



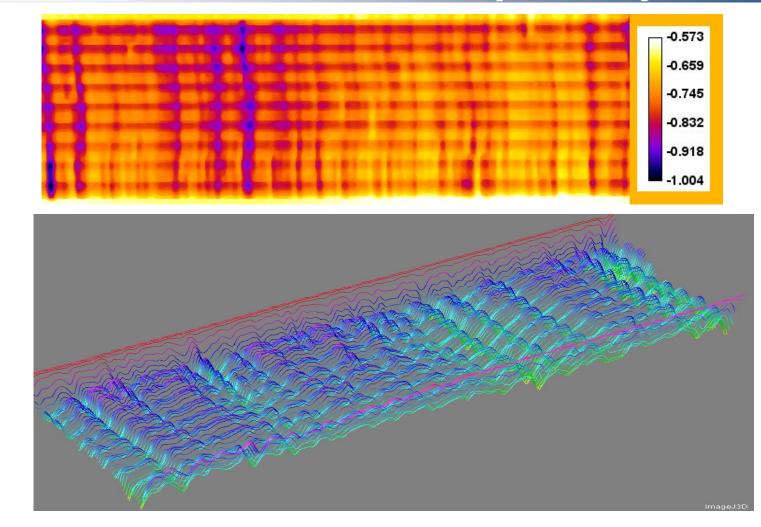
### Profilometry of Cylinder or Drum-Shaped Objects

#### 1.2m diameter motor commutator





### Profilometry of Cylinder or Drum-Shaped Objects Cont.



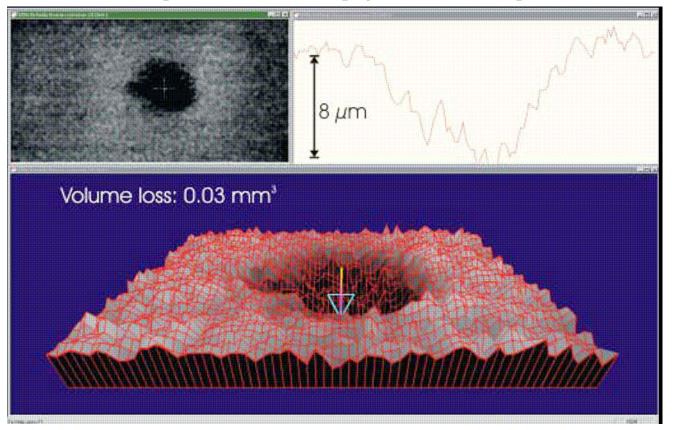
Flattened surface of a 1.2m-diameter motor commutator showing wear caused by contact of brushes

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## **Profilometry of LIBS Holes**

#### Very small hole created by Laser-Induced Breakdown Spectroscopy (LIBS) pulses



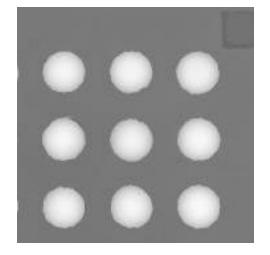
By combining LIBS and fiber profilometry, coatings in aerospace applications can be measured – e.g. in metal surfaces

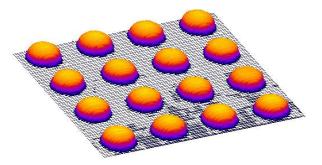


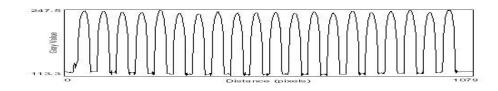
### Profilometry in Semi-Conductor Industry

#### Profiling of bumps on BGA packaging

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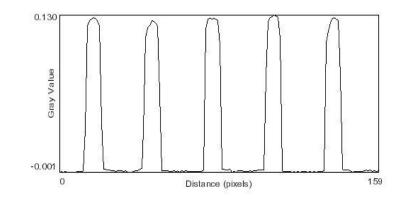


### Profilometry in the Semi-Conductor Industry

#### **Profiling of BGA flip chip**

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#### Ball height = 0.13mm or 130µm

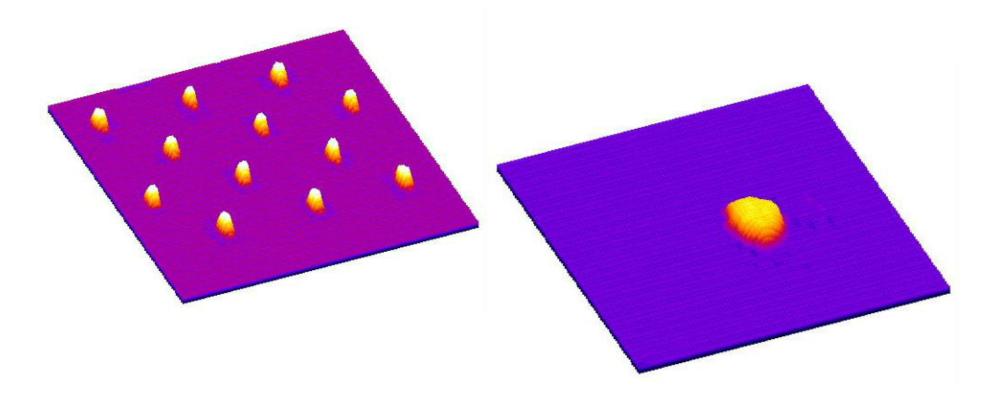


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### Profilometry in the Semi-Conductor Industry

#### **3D Rendering of flip chip**



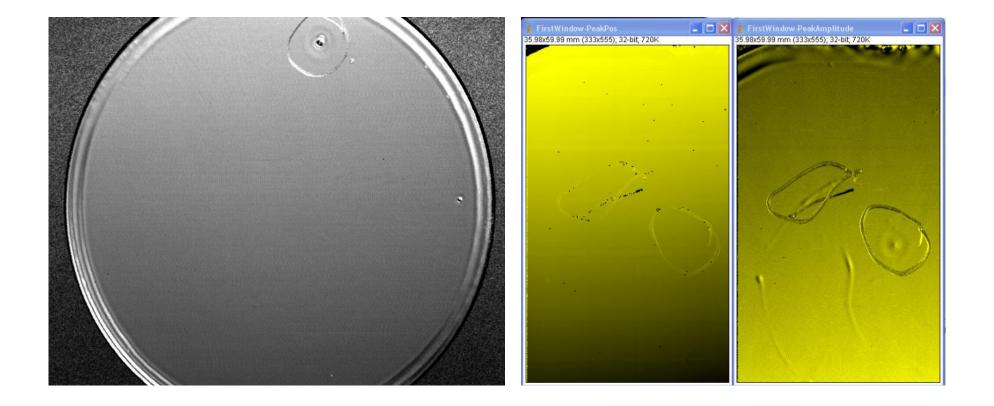
Ball height = 0.13mm or 130µm

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### **Sub-Micron Surface Defects**

#### Imaging surface defects in coatings of 4" wafers

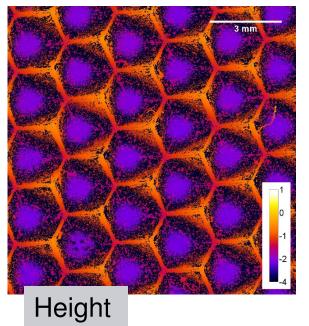


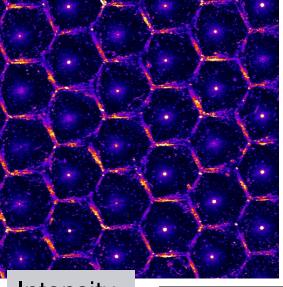


### Profilometry of Optical Elements

#### Car industry:

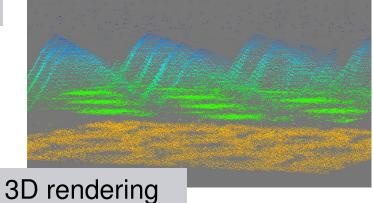
#### Imaging of metal mold for retro-reflector manufacture





Intensity

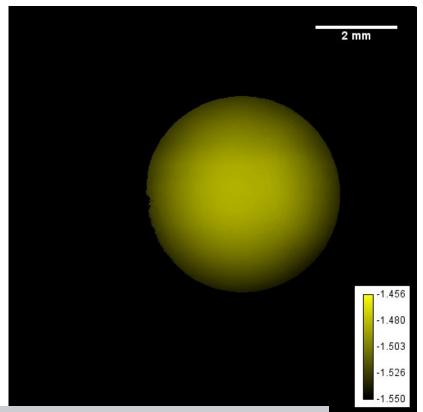
High sensitivity for imaging highly reflective surfaces





### Surface Mapping of Optical Elements

#### **3D surface mapping of lens**



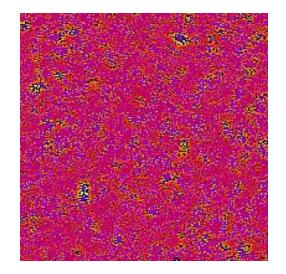
# Radius of lens measured from surface map

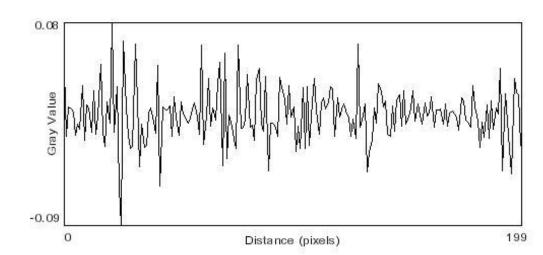
Image height represented by color intensity



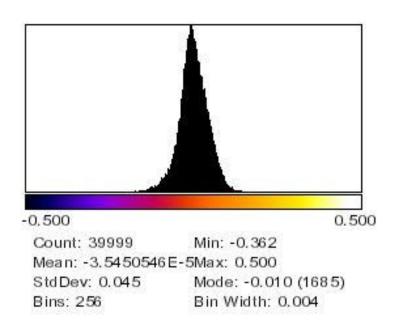
### Surface Roughness Measurements

#### **Plasma coated surface**





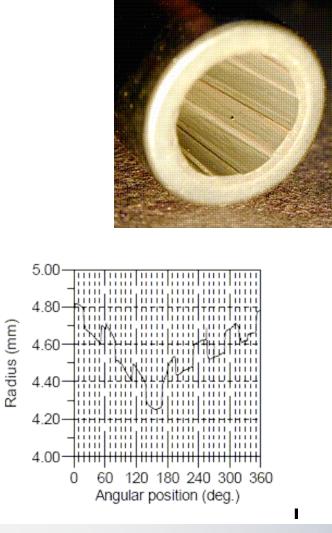
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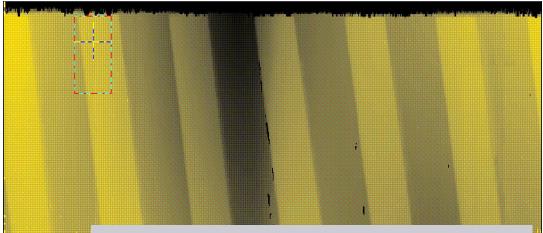




### Profilometry of Hard-to-Reach Surfaces

#### Profiling of inside wall of gun barrel





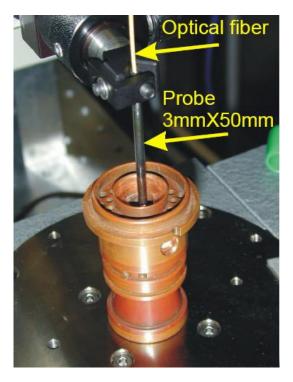
Mapping of inside surface, depth represented by color intensity

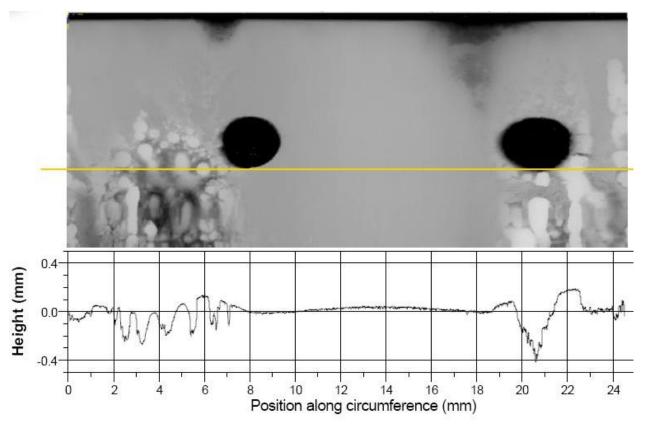
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### Internal Wall Profiling of Small Diameter Tube

#### **Plasma torch**





Mapping of inside wall surface



### Measurements in Hostile Environments

#### • High temperature

- Proximity of red-hot steel
- Proximity of plasma coating process
- Cryogenic
  - Cryogenic propulsion system
  - Liquid nitrogen level measurement in propulsion systems

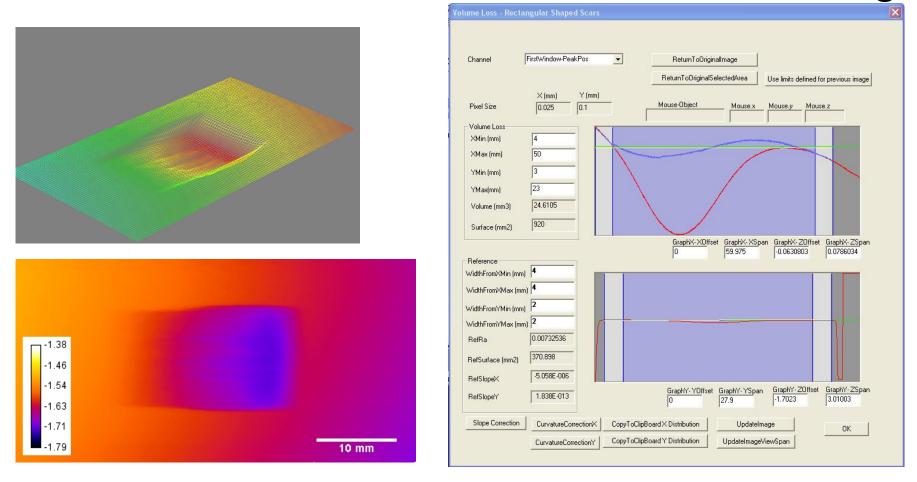
#### Radioactive

- Inspection of pitting of accelerator targets
- Crack inspection in nuclear facilities
- High vacuum
  - Evaporation chambers



### **Volume Loss Measurements**

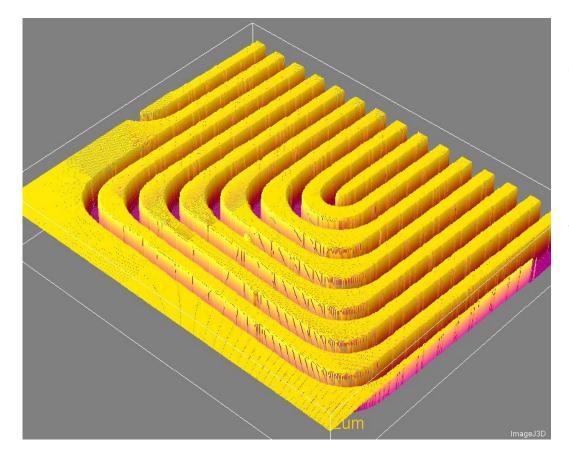
#### Measuring material wear for hardness measurements and scratch testing





### Profiling High-Aspect Ratio Surfaces

#### Profiling of bipolar plates in fuel cell

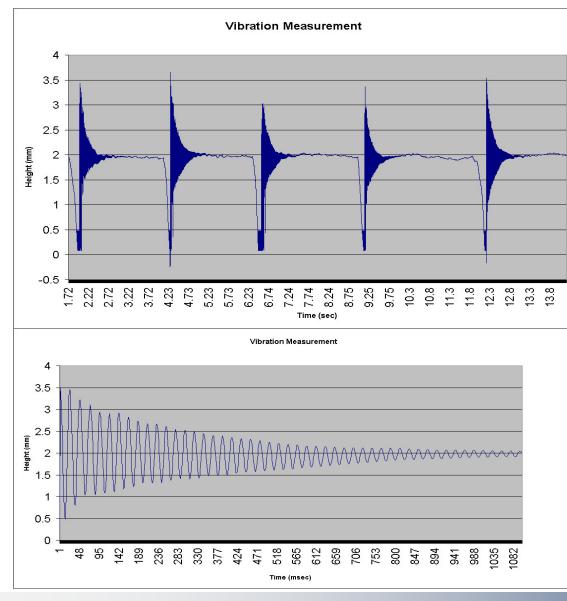


Advantage over triangulation sensors –does not need angle between sensor and light projection

# Light emitted and picked up with same probe



### **Vibration Measurements**



 Vibration frequency and intensity and shaft eccentricity can be measured with one or two probes mounted perpendicularly

 Multiple probes can be selected with optical switch (one at the time)



## **Profilometry Applications**

#### 1) Profilometry

#### 2) Thickness measurements of film or coating

- 3) Cross section imaging
- 4) On-line industrial and lab applications



### **Polymer Wall Thickness Measurements**

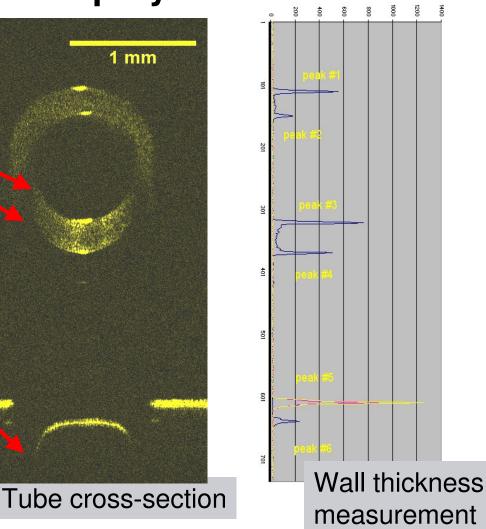
1 mm

#### Measuring wall thickness of polymer tube

Inside diameter (ID) Outside diameter (OD

Reference plane

Index of refraction calculated from change in distance of reference plane





### **Thickness Measurements**

#### Photo-resist coating on semi-conductor wafer



#### 6" diameter wafer with ~300 micron coating



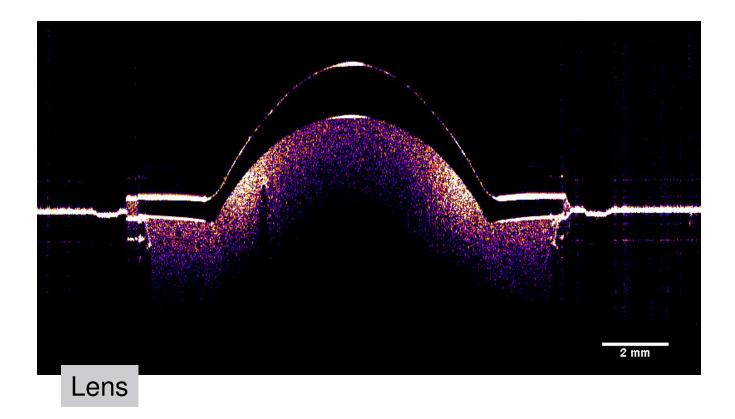
## **Profilometry Applications**

- 1) Profilometry
- 2) Thickness measurements of film or coating
- 3) Cross-section imaging
- 4) On-line industrial and lab applications



### **Cross-Section Imaging**

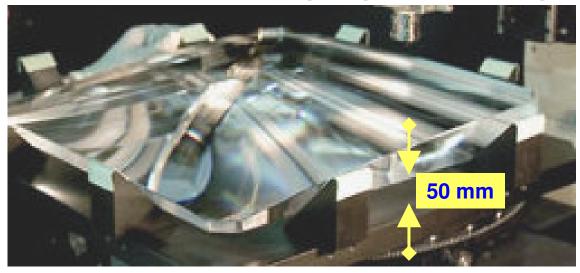
# Radius measurements of transparent optical elements

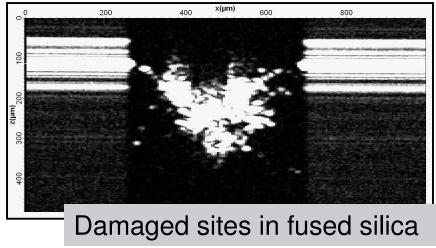




### **Cross-Section Imaging of Glass**

#### Sub-surface imaging of damage sites



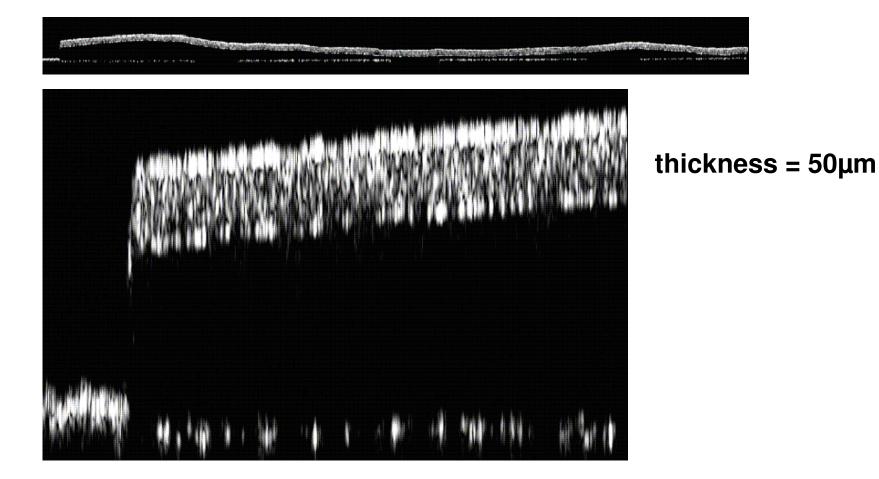


large optics 400mm x 400mm imaged through 50mm of glass



### Cross-section Imaging of Paper

#### Wax paper



35



### **Comparative Advantages**

- Small thin (1-12mm diameter) fiber-based probe
- Insensitive to environment lighting
- High-aspect ratio measurements
- High sensitivity and high resolution
- Ability to use multiple multiplexed probes
- Inhospitable environments
- Possible large standoff distance from probe
- Measurements possible far from detector enclosure
- Advantage over triangulation sensors
- Same probe can pick up IR ~900nm light of molten steel



### Accuracy Better Than 1µm

#### Profiling Mitutoyo step gage with steps of 1, 2, 5 and 10µm

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### **System Specifications**





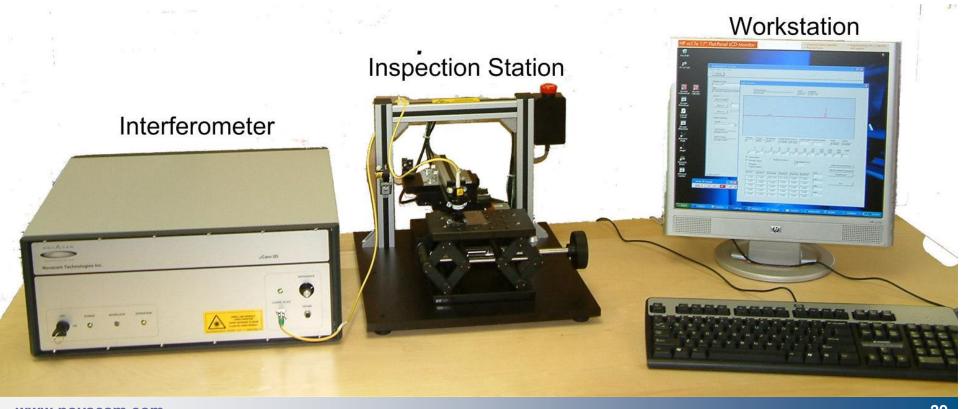
- Wavelength: 1,310 nm
- Acquisition rate: 1,000 20,000 points/second
- Depth range scanned : < 8mm
- Standoff distance: from few mm up to 1m
- Axial resolution: <1µm
- Lateral resolution: 8-25 μm
- Distance of probe from detector enclosure < 1km



### **Fiber-Based Profilometer**

#### **Typical lab setup**

#### Larger X-Y tables used for long stroke profilometry





#### Company





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